

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S3	167	circuit adj analysis and duplicat\$3 and (exclud\$3 sort\$3 eliminat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 14:53
S4	20	circuit adj analysis and duplicat\$3 and (exclud\$3 sort\$3 eliminat\$3) with result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 14:56
S5	23	circuit adj analysis and (replicat\$3 duplicat\$3) and (exclud\$3 sort\$3 eliminat\$3) with result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 14:57
S6	210	circuit adj analysis and (replicat\$3 duplicat\$3) and (exclud\$3 sort\$3 eliminat\$3) and result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 14:58
S7	29	circuit adj analysis and (replicat\$3 duplicat\$3) with result and (exclud\$3 sort\$3 eliminat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:02
S8	7	circuit adj analysis and (replicat\$3 duplicat\$3 "same" copy) near4 analysis near4 result and (exclud\$3 sort\$3 eliminat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:04
S9	174	circuit adj analysis and (replicat\$3 duplicat\$3 "same" copy) same analysis same result and (exclud\$3 sort\$3 eliminat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:06
S10	70	circuit adj analysis and (replicat\$3 duplicat\$3 "same" copy) same analysis same result and (exclud\$3 sort\$3 eliminat\$3) and filter\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:06

S11	5	circuit adj analysis and ERC	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:09
S12	2	circuit adj analysis and ERC and (duplicat\$3 replicat\$3 copy "same") with result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:12
S13	3	circuit adj2 analysis and ERC and (duplicat\$3 replicat\$3 copy "same") with result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:12
S14	1	circuit adj2 analysis and ERC and (duplicat\$3 replicat\$3 copy "same") with analysis adj2 result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 15:12
S15	16	circuit adj2 analysis and (duplicat\$3 replicat\$3 copy "same") with analysis adj2 result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:19
S16	2	"20050160386"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 17:31
S19	342	circuit adj analysis and result and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:26
S20	13	circuit adj analysis near3 result and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:31

S21	217	(circuit design)near4 analysis near3 result and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:32
S24	9	(circuit design)near4 analysis near4 result same (obtain\$3 input\$4 receiv\$3) same (duplicat\$3 copy replicat43 "same") near5 result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:42
S25	2	"20050160386"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:38
S26	584	(circuit design) same analysis same result same (obtain\$3 input\$4 receiv\$3) same (duplicat\$3 copy replicat43 "same") near5 result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:43
S27	37	(circuit design) with analysis with result same (obtain\$3 input\$4 receiv\$3) same (duplicat\$3 copy replicat43 "same") near5 result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:48
S28	325	(circuit design) with analysis with result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:49
S29	142	(circuit design) with analysis with result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same") same output\$4 same result\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:54
S30	275	(circuit design) same analysis near4 result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same") same output\$4 same result\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:55

S31	183	(circuit design) same analysis near4 result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same") same output\$4 same result\$3 and (exclud\$3 sort\$3 eliminat\$3 flag\$4 check\$3 delet\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 21:56
S32	13	(circuit design) same analysis near4 result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same") same output\$4 same result\$3 and (exclud\$3 sort\$3 eliminat\$3 flag\$4 check\$3 delet\$3) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:01
S33	25	(circuit design) same analysis near4 result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same") same (output\$4 result\$3) and (exclud\$3 sort\$3 eliminat\$3 flag\$4 check\$3 delet\$3) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:04
S34	419	(circuit design) same analysis near4 result same (obtain\$3 input\$4 receiv\$3 get\$4) same (duplicat\$3 cop\$4 replicat43 "same") same (output\$4 result\$3) and (exclud\$3 sort\$3 eliminat\$3 flag\$4 check\$3 delet\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:07
S35	14	duplicat\$3 adj2 (circuit design) adj2 result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:08
S36	139	(replicat\$3 duplicat\$3 copy "same") adj2 (circuit design) adj2 (result output\$4) and analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:09
S37	19	(replicat\$3 duplicat\$3 copy "same") adj2 (circuit design) adj2 (result output\$4) and analysis and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:10
S40	52	(replicat\$3 duplicat\$3 copy "same") with (circuit design) with (result output\$4) same analysis and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:14

S42	477	(replicat\$3 duplicat\$3 copy "same") with (circuit design) with (result output\$4)with analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:15
S43	88	(replicat\$3 duplicat\$3 copy "same") with (circuit design) with (result output\$4)with analysis same (identif\$4 determin\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:17
S45	3	(duplicat\$3) near4 (circuit design) near4(result output\$4)same analysis same (identif\$4 determin\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:19
S46	2	(duplicat\$3) adj2 (circuit design) adj2(result output\$4)same analysis same (identif\$4 determin\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:19
S47	3	(duplicat\$3) with (circuit design) adj2(result output\$4)same analysis same (identif\$4 determin\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:20
S48	2	(duplicat\$3) adj2 (circuit design) adj2(result output\$4)with analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:20
S49	12	(duplicat\$3 copy "same") near4 (circuit design) adj2(result output\$4)with analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:21
S51	39	(circuit design) with (result output\$4)with analysis same duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:23

S52	13	(circuit design) near4 analysis near4 (result output\$4)same analysis same duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:24
S53	7	(circuit design) near4 analysis near4 (result output\$4)same analysis same duplicat\$3 and filter\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:25
S54	47	(circuit design) near4 (result output\$4)same analysis same duplicat\$3 and filter\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:25
S55	79	(circuit design) near4 (result output\$4)same analysis same duplicat\$3 and (detect\$3 filter\$3 identif\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:26
S56	1	(circuit design) near4 (result output\$4)same analysis same duplicat\$3 and (detect\$3 filter\$3 identif\$4) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:26
S57	1	(circuit design) near4 (result\$3 output\$4)same analysis same duplicat\$3 and (detect\$3 filter\$3 identif\$4) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:27
S58	1	(circuit design) near4 (result\$3 output\$4 data)same analysis same duplicat\$3 and (detect\$3 filter\$3 identif\$4) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:27
S59	3	(circuit design) near4 (result\$3 output\$4 data)same analy\$4 same duplicat\$3 and (detect\$3 filter\$3 identif\$4) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:28

S61	30	(receiv\$3 obtain\$4 input\$4 get\$3 identif\$4) with (circuit design) with (result\$3 output\$4 data information) with duplicat\$ with anal\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:35
S65	55	(filter\$3 sort\$3) with (duplicat\$3 copy "same" replicat\$3) with analysis same (output data information result\$3) and type and defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:39
S66	24	analysis adj2 result near4 duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:41
S67	7	analysis adj2 result near4 duplicat\$3 and (circuit design)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/02 22:42
S68	3	analysis adj2 result near4 duplicat\$3 and (circuit) and type	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:29
S69	2	ERC adj2 violation same detect\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:00
S70	1	ERC adj2 violation same detect\$3 same duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:00
S71	6	(elctrical adj rule adj design ERC) same detect\$3 same duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:02

S72	3	(elctrical adj rule adj design ERC) same detect\$3 same duplicat\$3 same (signature result)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:07
S74	537	(elctrical adj rule adj design ERC) and analysis and result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:07
S75	106	(elctrical adj rule adj design ERC) and analysis and result and duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:08
S76	4	(elctrical adj rule adj design ERC) and analysis and result and duplicat\$3 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:12
S78	9	(elctrical adj rule adj design ERC) and analysis and (signature result) and (replicat\$3 copy "same" duplicat\$3) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:16
S79	10	(elctrical adj rule adj design ERC) and analysis and (signature result output data information) and (replicat\$3 copy "same" duplicat\$3) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:16
S80	527	(elctrical adj rule adj design ERC) and analysis and (signature result output data information) and (replicat\$3 copy "same" duplicat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:17
S81	19	(elctrical adj rule adj design ERC) same analysis same (signature result output data information) same (replicat\$3 copy "same" duplicat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:17

S82	2	(elctrical adj rule adj design ERC) same analysis same (signature result output data information) same (replicat\$3 duplicat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 10:17
S83	58668	(circuit design) with analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:31
S84	2	(ERC electrical adj rule adj check\$3) same detect\$3 same violat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:31
S85	2	S83 and S84	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:31
S86	1087041	(result output data information) same (identical duplicat\$3 copy "same") same (identif\$4 determin\$3 select\$3 sort\$3 eliminat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:36
S87	1	S83 and S84 and S86	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:36
S88	20282	S83 and S86	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:37
S89	1226	S83 and S86 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:37

S90	1080	S83 and S86 and "716"/\$.ccls. and type	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:37
S91	4	S83 and S86 and "716"/\$.ccls. and type and ERC	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 11:38
S92	7139	analysis with (duplicat\$3 replicat\$3 copy "same") with result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:20
S93	515	analysis with (duplicat\$3 replicat\$3 copy "same") with result same identif\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:21
S94	515	analysis with (duplicat\$3 replicat\$3 copy "same") with result same identif\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:25
S98	199	(circuit design) same analysis same (identical duplicat\$3 copy "same") same (result output data information) same (identif\$4 determin\$3 detect\$3 sort\$3 list\$3 select\$3 eliminat\$3)and type and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:38
S99	32	(circuit design) same analysis same (identical duplicat\$3 copy "same") same (result output data information) same (identif\$4 determin\$3 detect\$3 sort\$3 list\$3 select\$3 eliminat\$3)and type and ERC	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:41
S10 2	127	analysis with result with duplicat\$3 and (group\$3 class\$9 type categoriz\$3)and (circuit design)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:45

S10 3	1	analysis with result with duplicat\$3 and (group\$3 class\$9 type categoriz\$3)and (circuit design) and (electrical adj rule adj check\$3 ERC)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:47
S10 4	110	(identif\$4 determin\$3 detect\$3 sort\$3 check\$3 eliminat\$3 flag\$4) same analysis with result with duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:49
S10 5	1	(identif\$4 determin\$3 detect\$3 sort\$3 check\$3 eliminat\$3 flag\$4) same analysis with result with duplicat\$3 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 13:57
S10 6	185	(identif\$4 determin\$3 detect\$3 sort\$3 check\$3 eliminat\$3 flag\$4) same (ERC electrical adj rule adj check\$3 analysis) same result same (identical copy "same" duplicat\$3) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:06
S10 8	2029450	(duplicat\$4 copy identical\$2 "same") same (exclud\$3 exclusion remov\$3 eleiminat\$4 (get\$4 adj rid) dispose\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:45
S10 9	5111427	(sort\$3 order\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:37
S11 0	149916	(sort\$3 order\$3) same (defect\$3 fault bad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:37
S11 1	8215	716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:38

S11 2	0	S108 same S110 same S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:38
S11 3	137	S108 and S110 and S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:38
S11 4	48762	S108 and S110	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:47
S11 5	40534	S108 and S110 and type	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 14:48
S11 6	141	S108 and S110 and type and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 20:49
S11 7	2029450	(duplicat\$4 copy identical\$2 "same") same (exclud\$3 exclusion remov\$3 eleiminat\$4 (get\$4 adj rid) dispose\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 20:49
S11 8	149916	(sort\$3 order\$3) same (defect\$3 fault bad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 20:49
S11 9	85	S117 and S118 and type and "716"/\$.ccls. and analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 20:50

S12 0	74	S117 and S118 and type and "716"/\$.ccls. and analysis and @ad<"20040120"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 20:50
S12 1	1482174	(duplicat\$3 copy identical "same" copy) and anal\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:14
S12 2	544552	(duplicat\$3 copy identical "same" copy) same anal\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:14
S12 3	59117	(duplicat\$3 copy identical "same" copy) same anal\$6 same (result output data information) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:17
S12 4	128	(duplicat\$3 copy identical "same" copy) same anal\$6 same (result output data information) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:20
S12 5	1598	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:20
S12 6	5	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3) same sort\$3 same type and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:29
S12 7	0	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3) same sort\$3 same type and 716/1-18.ccls. and latch near5 defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:29

S12 8	1	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)and sort\$3 and type and 716/1-18.ccls. and latch near5 defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:30
S12 9	8	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)and sort\$3 and type and latch with defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:30
S13 0	87	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)and sort\$3 and type and (register FF flip-flop flip adj2 flop latch) with defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:33
S13 1	388	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)and sort\$3 and type and (register FF flip-flop flip adj2 flop latch) same defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:33
S13 2	61	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)same sort\$3 same type and (register FF flip-flop flip adj2 flop latch) same defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:35
S13 3	0	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)same sort\$3 same type and (register FF flip-flop flip adj2 flop latch) adj2 design same defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:36
S13 4	61	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)same sort\$3 same type and (register FF flip-flop flip adj2 flop latch) same defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:36
S13 5	0	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3)same sort\$3 same type and (register FF flip-flop flip adj2 flop latch) same defect and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/04 21:37

S13 6	34	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3) and sort\$3 and (group\$3 class\$5 type) and (register FF flip-flop flip adj2 flop latch) and defect and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:46
S13 7	2	"20050160386"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 12:25
S13 8	612	FET adj3 design	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 12:26
S13 9	2	FET adj3 design and analysis and result and duplicate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 12:26
S14 0	3	FET adj3 design and analysis and result and duplicat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 12:27
S14 1	1	FET adj3 design and analysis and result and duplicat\$3 and exclud\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 12:27
S14 2	2	"4827428".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 13:15
S14 3	2	"5003487".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 13:46

S14 8	38	((design circuit simulat\$3) with analy\$4) with (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) with (duplicat\$3 copy redundan\$2 "same") and 716/1-18.ccls. and @ad<"20040120"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 13:59
S14 9	38	((design circuit simulat\$3) with analy\$4) with (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) with (duplicat\$3 copy redundan\$2 "same") and 716/1-18.ccls. and @ad<"20040120"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 14:09
S15 0	30	((design circuit simulat\$3) with analy\$4) with (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) with (duplicat\$3 copy redundan\$2 "same") and (inquiry query) and @ad<"20040120"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 14:35
S15 2	3	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and sort\$3 near6 alphabetically	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:09
S15 3	1	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and sort\$3 near6 alphabetically and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:10
S15 4	1	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and sort\$3 same alphabetically and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:10
S15 5	4	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and sort\$3 and alphabetically and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:23

S15 6	75	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and sort\$3 and (group\$3 class\$9 type) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:25
S15 7	135	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and (list\$3 sort\$3) and (group\$3 class\$9 type) and clock and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:26
S15 8	89	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and (list\$3 sort\$3) and (group\$3 class\$9 type) and (clock gate near4 design MOS latch ff flip adj2 flop FET) and (defect violation) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:33
S16 0	43	((design circuit simulat\$3) with analy\$4) same (avoid\$3 eliminat\$3 sort\$3 select\$3 exclud\$3 list\$3 check\$3 flag\$4) same (duplicat\$3 copy redundan\$2 "same") and (list\$3 sort\$3) and (group\$3 class\$9 type) and (gate near4 design MOS FET) and clock and (latch ff flip adj flop)and (defect violation) and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 15:36
S16 1	0	(duplicat\$3 copy identical "same" copy) same (exclud\$3 exclusion remov\$3 eliminat\$3 (get adj rid adj of) dipos\$3) and (list\$3 sort\$3) and (group\$3 class\$5 type) and (register FF flip-flop flip adj2 flop latch)and clock and MOS and EFT and defect and 716/1-18.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:47
S16 2	30580	analysis adj result	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:48

S16 3	24586	(defect violation)same (simulat\$3 design)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:49
S16 4	372	S162 and S163	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:49
S16 5	93	S162 and S163 and clock	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:49
S16 6	46	S162 and S163 and clock and latch	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:50
S16 7	0	S162 and S163 and clock and latch and EFT	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:50
S16 8	5	S162 and S163 and clock and latch and MOS	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:50
S16 9	45	S162 and S163 and clock and latch and (gate MOS)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:50
S17 0	0	S162 and S163 and clock and latch and (gate MOS) and EFT	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:50

S17 1	16	S162 and S163 and clock and latch and (gate MOS) and (transistor EFT)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:57
S17 2	1	S162 and S163 and clock and latch and (FET) and (transistor EFT)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:58
S17 3	74	S162 and S163 and (transistor EFT)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:58
S17 4	16	S162 and S163 and (transistor EFT) and latch	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:58
S17 5	16	S162 and S163 and (transistor EFT) and latch and clock	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:59
S17 6	16	S162 and S163 and (transistor EFT) and latch and clock and gate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 16:59
S17 7	5	S162 and S163 and (transistor EFT) and latch and clock and gate and MOS	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 17:01
S17 8	4	S162 and S163 and (transistor EFT) and latch and clock and gate and (NMOS nmos)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 17:02

S17 9	4	S162 and S163 and (transistor EFT) and latch and clock and gate and (NMOS nmos) and type	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 18:44
S18 0	2086	716/4.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/05 18:51